

Title (en)

ELECTROMIGRATION TEST DEVICE AND ELECTROMIGRATION TEST METHOD

Title (de)

ELEKTROMIGRATIONS-TESTVORRICHTUNG UND ELEKTROMIGRATIONS-TESTVERFAHREN

Title (fr)

DISPOSITIF DE TEST D'ELECTROMIGRATION ET PROCEDE ASSOCIE

Publication

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Application

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Priority

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Abstract (en)

[origin: WO2004001432A1] The invention relates to an electromigration test device comprising a direct-current source (101) and an alternating voltage source (102). Said device also comprises a circuit (104) which has a conductive structure (100) and is electrically coupled to the direct-current source (101) and to the alternating voltage source (102), and a measuring device for measuring an electrical parameter which indicates electromigration in the conductive structure. The alternating voltage source (102) is controlled in such a way that it subjects the conductive structure (100) to an alternating current, independently of a direct current, thus heating the conductive structure (100) to a pre-determined temperature.

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IPC 8 full level

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